

1.2.5 Lead finish. The lead finish shall be as specified in MIL-M-38510 for classes M, B, and S or MIL-I-38535 for classes Q and V. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

1.3 Absolute maximum ratings. 1/

Supply voltage range	-0.5 V dc to +7.0 V dc
DC input voltage range	-0.5 V dc to $V_{CC} + 0.5$ V dc
DC output voltage range	-0.5 V dc to $V_{CC} + 0.5$ V dc
DC input diode current	± 20 mA
DC output diode current (per output pin)	± 20 mA
DC output source or sink current (per output pin)	± 50 mA
DC V_{CC} or GND current	± 50 mA
Storage temperature range	-65°C to +150°C
Maximum power dissipation (P_D)	500 mW
Lead temperature (soldering, t_{10} seconds)	+300°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-M-38510, appendix C
Junction temperature (T_J) 2/	+175°C

1.4 Recommended operating conditions.

Supply voltage range (V_{CC})	4.5 V dc to 5.5 V dc
Input voltage range	0.0 V dc to V_{CC}
Output voltage range	0.0 V dc to V_{CC}
Case operating temperature range (T_C)	-55°C to +125°C
Input rise or fall times: $V_{CC} = 4.5$ V to 5.5 V	0 to 8 ns/V
Minimum setup time, data (Dn) to clock (CP) (t_{s1}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	3.5 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	4.0 ns
Minimum setup time, enable (EN) to CP (t_{s2}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	3.5 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	4.0 ns
Minimum hold time, Dn to CP (t_{h1}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	2.5 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	2.5 ns
Minimum hold time, EN to CP (t_{h2}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	1.0 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	2.0 ns
Minimum pulse width, CP High, low (t_{w1}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	6.0 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	6.0 ns
Minimum pulse width, clear (CLR) low, (t_{w2}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	6.0 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	7.0 ns
Minimum recovery time, CLR to CP (t_{rec}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	4.0 ns
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	4.5 ns
Maximum clock frequency (f_{MAX}): $T_C = +25^\circ\text{C}, V_{CC} = 4.5$ V	95 MHz
$T_C = -55^\circ\text{C}, +125^\circ\text{C}, V_{CC} = 4.5$ V	95 MHz

1/ Unless otherwise specified, all voltages are referenced to GND.

2/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with method 5004 of MIL-STD-883.

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1.5 Digital logic testing for device classes Q and V.

Fault coverage measurement of manufacturing logic tests (MIL-STD-883, test method 5012) - - - XX percent 3/

2. APPLICABLE DOCUMENTS

2.1 Government specifications, standards, bulletin, and handbook. Unless otherwise specified, the following specifications, standards, bulletin, and handbook of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATIONS

MILITARY

- MIL-I-38535 - Integrated Circuits, Manufacturing, General Specification for.
- MIL-M-38510 - Microcircuits, General Specification for.

STANDARDS

MILITARY

- MIL-STD-480 - Configuration Control-Engineering Changes, Deviations and Waivers.
- MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

- MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

HANDBOOK

MILITARY

- MIL-HDBK-780 - Standardized Military Drawings.

(Copies of the specifications, standards, bulletin, and handbook required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device class M shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein. The individual item requirements for device classes B and S shall be in accordance with MIL-M-38510 and as specified herein. For device classes B and S, a full electrical characterization table for each device type shall be included in this SMD. The individual item requirements for device classes Q and V shall be in accordance with MIL-I-38535, the device manufacturer's Quality Management (QM) plan, and as specified herein.

3/ Values will be added when they become available.

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3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 for device classes M, B, and S and MIL-I-38535 for device classes Q and V and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. Marking for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein). In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103. Marking for device classes B and S shall be in accordance with MIL-M-38510. Marking for device classes Q and V shall be in accordance with MIL-I-38535.

3.5.1 Certification/compliance mark. The compliance mark for device class M shall be a "C" as required in MIL-STD-883 (see 3.1 herein). The certification mark for device classes B and S shall be a "J" or "JAN" as required in MIL-M-38510. The certification mark for device classes Q and V shall be a "QML" as required in MIL-I-38535.

3.6 Certificate of compliance. For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.7.3 herein). For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.7.2 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device class M the requirements of MIL-STD-883 (see 3.1 herein), or for device classes Q and V, the requirements of MIL-I-38535 and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required for device class M in MIL-STD-883 (see 3.1 herein) or device classes B and S in MIL-M-38510 or for device classes Q and V in MIL-I-38535 shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DESC-ECS of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-STD-480.

3.9 Verification and review for device class M. For device class M, DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device classes M, B, and S. Device classes M, B, and S devices covered by this drawing shall be in microcircuit group number 38 (see MIL-M-38510, appendix E).

3.11 Serialization for device class S. All device class S devices shall be serialized in accordance with MIL-M-38510.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device class M, sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein). For device classes B and S, sampling and inspection procedures shall be in accordance with MIL-M-38510 and method 5005 of MIL-STD-883, except as modified herein. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-I-38535 and the device manufacturer's QM plan.

4.2 Screening. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. For device classes B and S, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to qualification and quality conformance inspection. For device classes Q and V, screening shall be in accordance with MIL-I-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection.

4.2.1 Additional criteria for device classes M, B, and S.

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. For device class M, the test circuit shall be submitted to DESC-ECS for review with the certificate of compliance. For device classes B and S, the test circuit shall be submitted to the qualifying activity.

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table IIA herein. Interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.2.2 Additional criteria for device classes Q and V.

a. The burn-in test duration, test condition and test temperature or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The burn-in test circuit shall be submitted to DESC-ECS with the certificate of compliance and shall be under the control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-I-38535.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in appendix B of MIL-I-38535 and as detailed in table IIB herein.

4.3 Qualification inspection.

4.3.1 Qualification inspection for device classes B and S. Qualification inspection for device classes B and S shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

4.3.2 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-I-38535. Inspections to be performed shall be those specified in MIL-I-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
High level output voltage	V _{OH}	V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OH} = 150 μA 1/	V _{CC} = 4.5 V	1, 2, 3	4.4	V
					V _{CC} = 5.5 V	
		V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OH} = 24 mA 1/	V _{CC} = 4.5 V		3.7	
			V _{CC} = 5.5 V		4.7	
V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OH} = 50 mA 1/	V _{CC} = 5.5 V	3.85				
Low level output voltage	V _{OL}	V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OL} = 50 μA 1/	V _{CC} = 4.5 V	1, 2, 3	0.1	V
					V _{CC} = 5.5 V	
		V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OL} = 24 mA 1/	V _{CC} = 4.5 V		0.5	
			V _{CC} = 5.5 V		0.5	
V _{IN} = V _{IH} minimum or V _{IH} maximum, I _{OL} = 50 mA 1/	V _{CC} = 5.5 V	1.65				
High level input voltage	V _{IH}	2/	V _{CC} = 4.5 V	1, 2, 3	2.0	V
			V _{CC} = 5.5 V		2.0	
Low level input voltage	V _{IL}	2/	V _{CC} = 4.5 V	1, 2, 3	0.8	V
			V _{CC} = 5.5 V		0.8	
Input leakage current	I _{IL}	V _{IN} = 0.0 V	V _{CC} = 5.5 V	1, 2, 3	-1.0	μA
	I _{IH}	V _{IN} = 5.5 V			1.0	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _c ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Maximum I _{CC} /input current	delta I _{CC}	V _{CC} = 5.5 V, input under test = V _{CC} - 2.1 V, all other inputs = V _{CC} or GND 3/	1, 2, 3		1.6	mA
Quiescent supply	I _{CCH}	V _{IN} = V _{CC} or GND V _{CC} = 5.5 V I _{OUT} = 0.0 V	1, 2, 3		160	μA
	I _{CCL}				160	
	I _{CCZ}				160	
Off-state output leakage current	I _{OZH}	V _{OEN} = V _{IH} minimum or V _{IH} maximum, V _{CC} = 5.5 V, all other inputs = V _{CC} or GND, V _{OUT} = 5.5 V or 0.0 V, test with each OEN = V _{IH} minimum separately	1, 2, 3		+10.0	μA
	I _{OZL}	V _{OEN} = V _{IH} minimum or V _{IH} maximum, V _{CC} = 5.5 V, All other inputs = V _{CC} or GND, V _{OUT} = GND, test with each OEN = V _{IH} minimum separately			-10.0	μA
Input capacitance	C _{IN}	See 4.4.1c	4		4.5	pF
Output capacitance	C _{OUT}	See 4.4.1c	4		4.5	pF
Power dissipation capacitance	C _{PD}	See 4.4.1c 4/	4		4.4	pF
Functional tests		Tested at V _{CC} = 4.5 V and repeated at V _{CC} = 5.5 V, see 4.4.1d	7,8			
Propagation delay time, CP to On	t _{PHL1}	C _L = 50 pF minimum, R _L = 500Ω, V _I = 4.5 V, see figure 4 5/	9	1.0	9.5	ns
			10,11	1.0	11.5	
	t _{PLH1}		9	1.0	9.5	ns
			10,11	1.0	11.5	
Propagation delay time, CLR to On	t _{PHL2}	C _L = 50 pF minimum, R _L = 500Ω, V _I = 4.5 V, see figure 4 5/	9	1.0	14.5	ns
			10,11	1.0	18.0	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _c ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Output enable time, OE to On	t _{PZH}	V _{CC} = 4.5 V, C _{CC} = 50 pF minimum, R _L = 500Ω, see figure 4 5/	9	1.0	9.5	ns
			10,11	1.0	11.5	
	t _{PZL}		9	1.0	10.5	
			10,11	1.0	12.5	
Output disable time, OE to On	t _{PHZ}	V _{CC} = 4.5 V, C _{CC} = 50 pF minimum, R _L = 500Ω, see figure 4 5/	9	1.0	11.5	ns
			10,11	1.0	13.5	
	t _{PLZ}		9	1.0	10.5	
			10,11	1.0	13.0	

- 1/ V_{OH} and V_{OL} tests will be tested at V_{CC} = 4.5 V. V_{OH} and V_{OL} are guaranteed, if not tested for V_{CC} = 5.5 V. Limits shown apply to operation at V_{CC} = 5.0 V ± 0.5 V. Transmission driving tests are performed at V_{CC} = 5.5 with a 2 ms duration maximum.
- 2/ V_{IH} and V_{IL} tests are not required if applied as a forcing function for the V_{OH} and V_{OL} tests.
- 3/ Delta I_{CC(max)}/pin ≤ 1.6 mA (preferred method), or delta I_{CC}/package ≤ 1.6 mA x the number of input pins/package where delta I_{CC(max)}/data pin ≤ 1.6 mA and delta I_{CC(max)}/control pin ≤ 3.0 mA (alternate method).
- 4/ Power dissipation capacitance C_{PD}, determines the dynamic power consumption,

$$P_D = (C_{PD} + C_L) (V_{CC})^2 f + I_{CC} (V_{CC})$$
, and the dynamic current consumption (I_S) is,

$$I_S = (C_{PD} + C_L) V_{CC} f + I_{CC}$$
- 5/ AC limits at V_{CC} = 5.5 V are equal to limits at V_{CC} = 4.5 V and guaranteed by testing at V_{CC} = 4.5 V. Minimum ac limits are guaranteed for V_{CC} = 5.5 V by guardbanding the V_{CC} = 4.5 V minimum limits to 1.5 ns.

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Device type	01	
Case outlines	K and L	3
Terminal number	Terminal symbol	
1	$\overline{OE1}$	NC
2	OE2	$\overline{OE1}$
3	D0	OE2
4	D1	D0
5	D2	D1
6	D3	D2
7	D4	D3
8	D5	NC
9	D6	D4
10	$\overline{D7}$	D5
11	CLR	D6
12	GND	$\overline{D7}$
13	\overline{CP}	CLR
14	EN	GND
15	07	NC
16	06	\overline{CP}
17	05	EN
18	04	07
19	03	06
20	02	05
21	01	04
22	$\overline{00}$	NC
23	OE3	03
24	V	02
25	-CC	01
26	---	$\overline{00}$
27	---	OE3
28	---	V _{CC}

Terminal names	Description
D0-07	Data inputs
$\overline{00}$ -07	Data outputs
$\overline{OE1}$, OE2, OE3	Output enables
EN	Clock enable
CLR	Clear
CP	Clock input

FIGURE 1. Terminal connections.

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Inputs					Output		Output function	
$\overline{OE}n^*$	\overline{CLR}	\overline{EN}	CP	Dn	Internal On	External On	Internal	External
H	X	L	↗	L	H	Z	Load	High-Z
H	X	L	↗	H	L	Z	Load	High-Z
H	L	X	X	X	H	Z	Clear	High-Z
L	L	X	X	X	H	L	Clear	Clear
H	H	H	X	X	NC	Z	Hold	High-Z
L	H	H	X	X	NC	NC	Hold	Hold
H	H	L	↗	L	H	Z	Load	High-Z
H	H	L	↗	H	L	Z	Load	High-Z
L	H	L	↗	L	H	L	Load	Load
L	H	L	↗	H	L	H	Load	Load

H = High voltage level
 L = Low voltage level
 X = Immaterial
 Z = High impedance
 ↗ = Low-to-high transition
 NC = No change
 * = Outputs On enabled if $\overline{OE}1 = \overline{OE}2 = \overline{OE}3 = L$

FIGURE 2. Truth table.

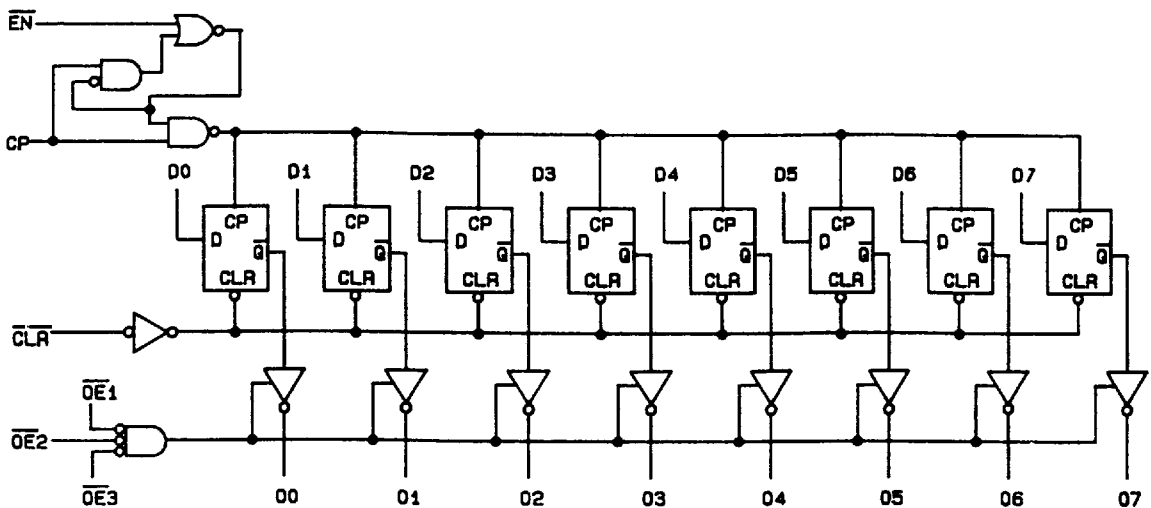


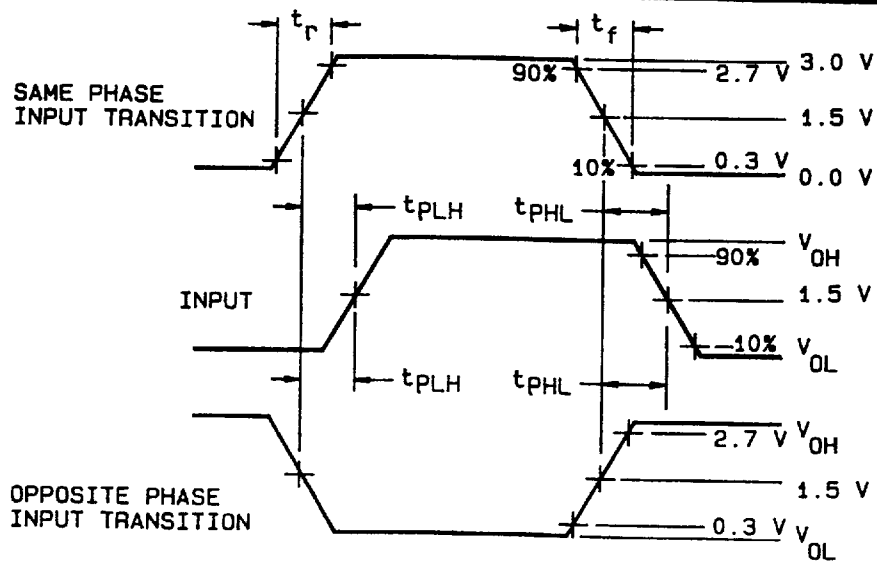
FIGURE 3. Logic diagram.

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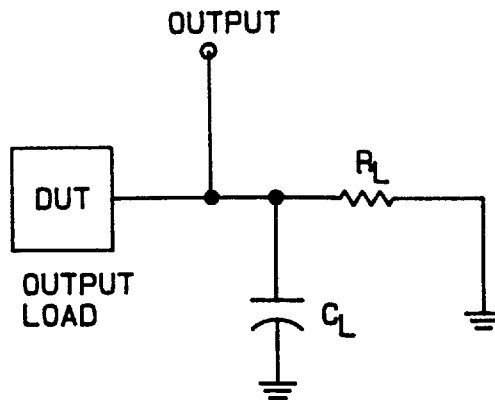
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Input $t_r, t_f = 3.0$ ns, unless otherwise specified.



$C_L = 50$ pF minimum, $R_L = 500\Omega$ or equivalent.

C_L includes probe and jig capacitance.

FIGURE 4. Switching waveforms and test circuit.

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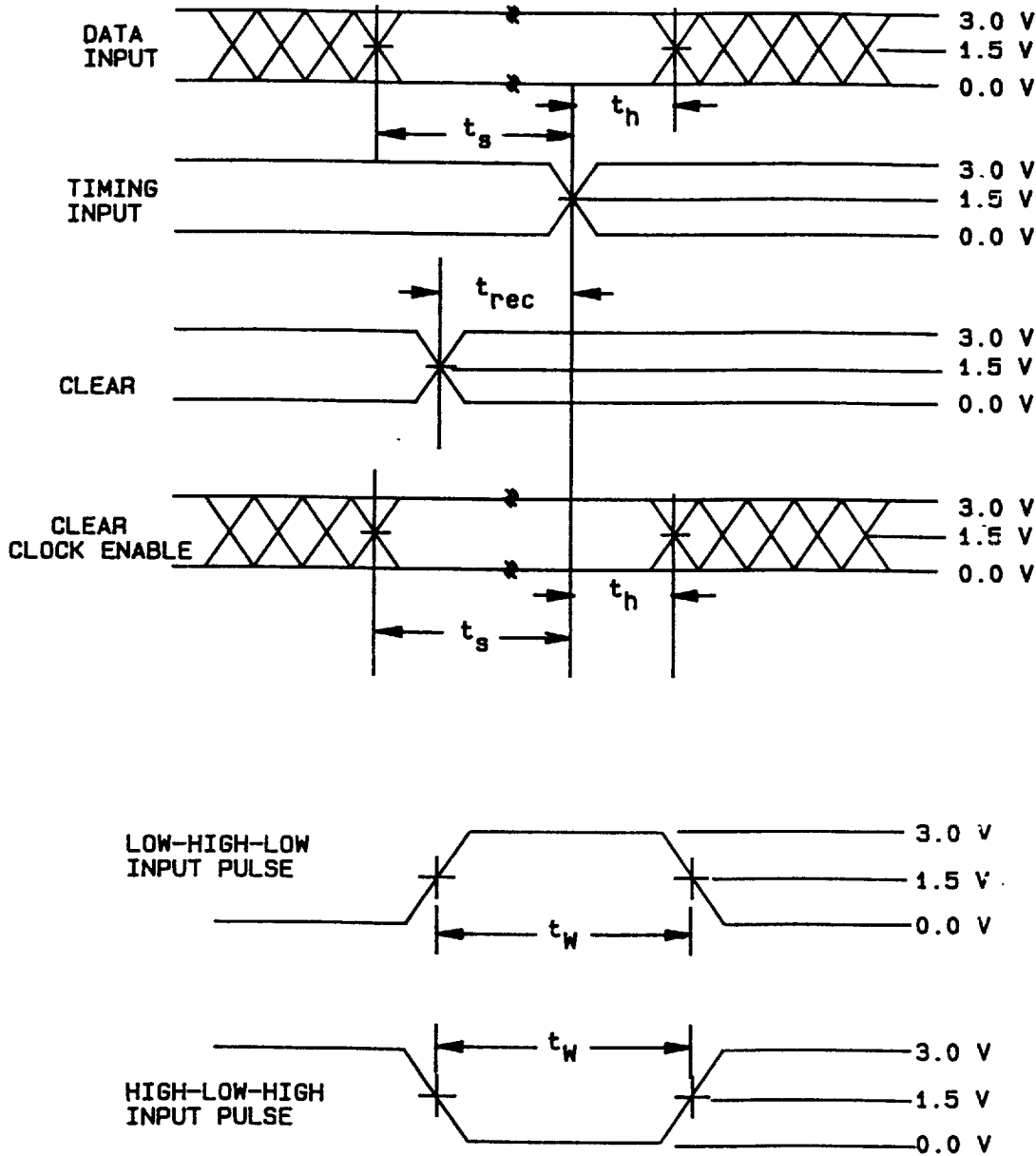


FIGURE 4. Switching waveforms and test circuit - Continued.

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4.4 Conformance inspection. Quality conformance inspection for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein) and as specified herein. Quality conformance inspection for device classes B and S shall be in accordance with MIL-M-38510 and as specified herein. Inspections to be performed for device classes M, B, and S shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5). Technology conformance inspection for classes Q and V shall be in accordance with MIL-I-38535 including groups A, B, C, D, and E inspections and as specified herein except where option 2 of MIL-I-38535 permits alternate in-line control testing.

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_{IN} , C_{OUT} , and C_{PD} measurements) shall be measured only for the initial test and after process or design changes which may affect capacitance. Capacitance shall be measured between the designated terminal and GND at a frequency of 1 MHz. Test all applicable pins on 5 devices with zero failures.
- d. For device class M, subgroups 7 and 8 tests shall be sufficient to verify the truth table. For device classes B and S, subgroups 7 and 8 tests shall be sufficient to verify the truth table as approved by the qualifying activity. For device classes Q and V, subgroups 7 and 8 shall include verifying the functionality of the device; these tests shall have been fault graded in accordance with MIL-STD-883, test method 5012 (see 1.5 herein).

4.4.2 Group B inspection. The group B inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.3 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.3.1 Additional criteria for device classes M, B, and S. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C, or D. For device class M, the test circuit shall be submitted to DESC-ECS for review with the certificate of compliance. For device classes B and S, the test circuit shall be submitted to the qualifying activity.
- b. $T_A = +125^\circ\text{C}$, minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.3.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The steady-state life test circuit shall be submitted to DESC-ECS with the certificate of compliance and shall be under the control of the device manufacturer's TRB in accordance with MIL-I-38535.

4.4.4 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

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DESC FORM 193A
SEP 87

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TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (per method 5005, table I)			Subgroups (per MIL-I-38535, table III)	
	Device class M	Device class B	Device class S	Device class Q	Device class V
Interim electrical parameters (see 4.2)		1	1	1	1
Final electrical parameters (see 4.2)	1/ 1,2,3,7, 8,9	1/ 1,2,3,7, 8,9,10,11	1/ 1,2,3,7, 8,9,10,11	1/ 1,2,3,7, 8,9,10,11	1/ 1,2,3,7, 8,9,10,11
Group A test requirements (see 4.4)	1,2,3,4, 7,8,9,10,11	1,2,3,4, 7,8,9,10,11	1,2,3,4, 7,8,9,10,11	1,2,3,4, 7,8,9,10,11	1,2,3,4, 7,8,9,10,11
Group B end-point electrical parameters (see 4.4)			1,2,3, 9,10,11		1,2,3, 9,10,11
Group C end-point electrical parameters (see 4.4)	1,2,3	1,2,3		1,2,3	
Group D end-point electrical parameters (see 4.4)	1,2,3	1,2,3	1,2,3	1,2,3	1,2,3
Group E end-point electrical parameters (see 4.4)	1,7,9	1,7,9	1,7,9	1,7,9	1,7,9

1/ PDA applies to subgroup 1.

4.4.5 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes B, S, Q, and V shall be M, D, R, and H and for device class M shall be M and D. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.

- a. RHA tests for device classes B and S for levels M, D, R, and H or for device class M for levels M and D shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
- b. End-point electrical parameters shall be as specified in table IIA herein.
- c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table IIA herein.
- d. For device classes M, B, and S, the devices shall be subjected to radiation hardness assured tests as specified in MIL-M-38510 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at $T_A = +25^\circ\text{C} \pm 5$ percent, after exposure.

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TABLE IIB. Additional screening for device class V.

Test	MIL-STD-883, test method	Lot requirement
Particle impact noise detection	2020	100%
Internal visual	2010, condition A or approved alternate	100%
Nondestructive bond pull	2023 or approved alternate	100%
Reverse bias burn-in	1015	100%
Burn-in	1015, total of 240 hours at +125°C	100%
Radiographic	2012	100%

- e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
- f. For device classes M, B, and S, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
- g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510 for device classes M, B, and S and MIL-I-38535 for device classes Q and V.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.1.2 Substitutability. Device classes B and Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.3 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and which SMD's are applicable to that system. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

6.4 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.

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6.5 Symbols, definitions, and functional descriptions.

GND	-----	Ground zero voltaa potential.
I _{CC}	-----	Quiescent supply current.
I _{IH}	-----	Input current high.
I _{IL}	-----	Input current low.
T _C	-----	Case temperature.
V _{CC}	-----	Positive supply voltage.

6.6 One part - one part number system. The one part - one part number system described below has been developed to allow for transitions between identical generic devices covered by the four major microcircuit requirements documents (MIL-M-38510, MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The four military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all four documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

<u>Military documentation format</u>	<u>Example PIN under new system</u>	<u>Manufacturing source listing</u>	<u>Document listing</u>
New MIL-M-38510 Military Detail Specifications (in the SMD format)	5962-XXXXXZZ(B or S)YY	QPL-38510 (Part 1 or 2)	MIL-BUL-103
New MIL-H-38534 Standardized Military Drawings	5962-XXXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standardized Military Drawings	5962-XXXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standardized Military Drawings	5962-XXXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 Sources of supply.

6.7.1 Sources of supply for device classes B and S. Sources of supply for device classes B and S are listed in QPL-38510.

6.7.2 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DESC-ECS and have agreed to this drawing.

6.7.3 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.

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STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 91-11-01

Approved sources of supply for SMD 5962-91611 are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECS. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN ^{1/}
5962-9161101MKX	27014	54ACT825FMQB
5962-9161101MLX	27014	54ACT825SDMQB
5962-9161101M3X	27014	54ACT825LMQB

^{1/} Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

27014

Vendor name and address

National Semiconductor
 2900 Semiconductor Drive
 P.O. Box 58090
 Santa Clara, CA 95052-8090
 Point of contact: 333 Western Avenue
 South Portland, ME 04106

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.

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